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(12) **United States Design Patent** (10) **Patent No.:** **US D983,681 S**  
**Chen et al.** (45) **Date of Patent:** **\*\* Apr. 18, 2023**

(54) **PROBE FOR TESTING DEVICE UNDER TEST**

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(73) Assignee: **MPI CORPORATION**, Chu-pei (TW)  
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Dec. 3, 2020 (TW) ..... 109306823  
(51) **LOC (14) Cl.** ..... **10-04**  
(52) **U.S. Cl.**  
USPC ..... **D10/80**  
(58) **Field of Classification Search**  
USPC ..... D10/78, 80  
(Continued)

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(Continued)

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(74) *Attorney, Agent, or Firm* — Birch, Stewart, Kolasch & Birch, LLP

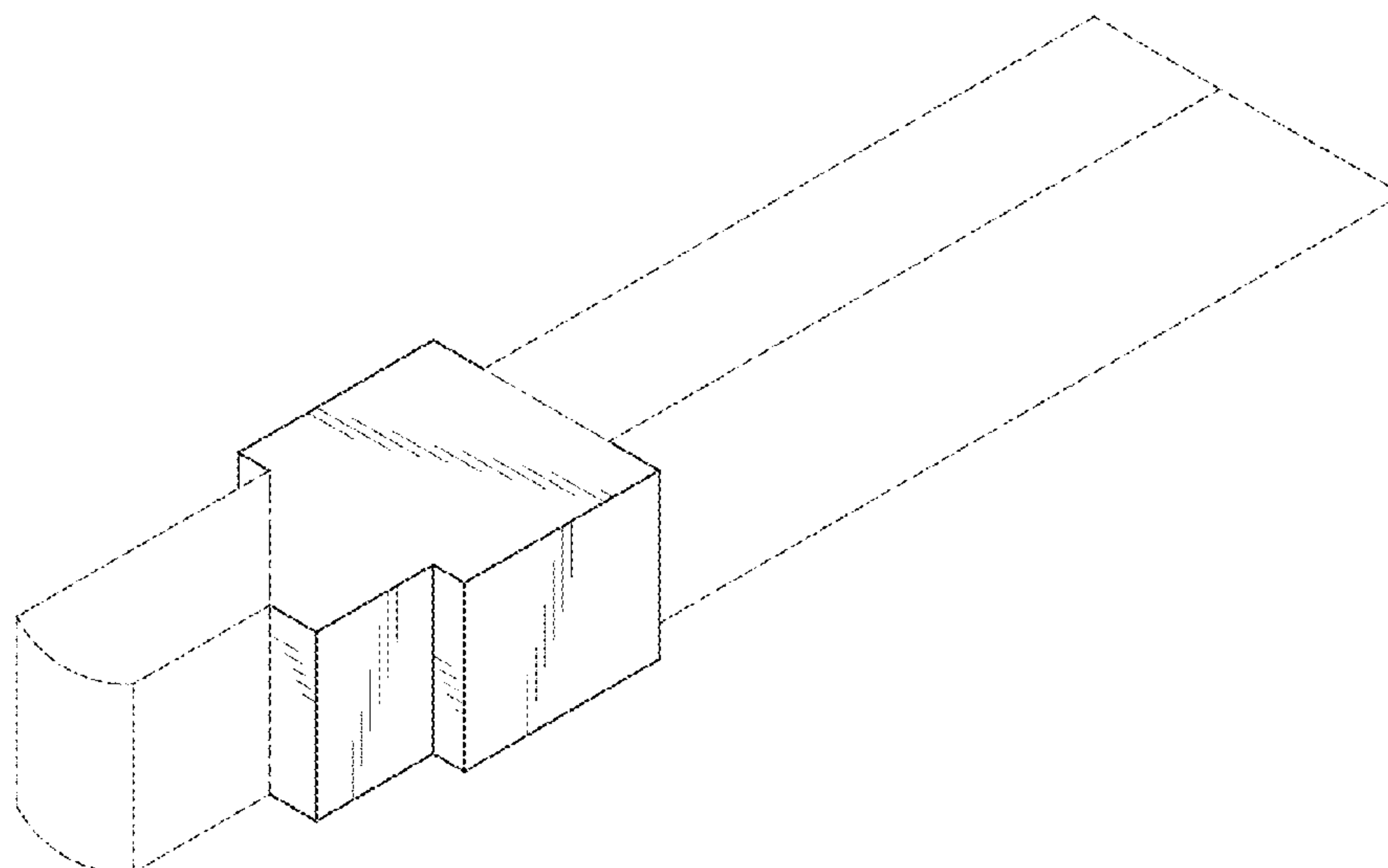
(57) **CLAIM**

The ornamental design for a probe for testing a device under test, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of a first embodiment of a probe according to our design;  
FIG. 2 is an enlarged, broken away perspective view taken along line A-A on FIG. 1;  
FIG. 3 is an enlarged, broken away front view taken along line A-A on FIG. 1;  
FIG. 4 is an enlarged, broken away rear view taken along line A-A on FIG. 1;  
FIG. 5 is an enlarged left side elevational view of the first embodiment of the probe shown in FIG. 1;  
FIG. 6 is an enlarged right side elevational view of the first embodiment of the probe shown in FIG. 1;  
FIG. 7 is an enlarged, broken away top plan view taken along line A-A on FIG. 1;  
FIG. 8 is an enlarged, broken away bottom plan view taken along line A-A on FIG. 1;  
FIG. 9 is another enlarged, broken away perspective view taken along line A-A on FIG. 1;  
FIG. 10 is a perspective view of a second embodiment of a probe according to our design;  
FIG. 11 is an enlarged, broken away perspective view taken along line B-B on FIG. 10;  
FIG. 12 is an enlarged, broken away front view taken along line B-B on FIG. 10;  
FIG. 13 is an enlarged, broken away rear view taken along line B-B on FIG. 10;  
FIG. 14 is an enlarged left side elevational view of the second embodiment of the probe shown in FIG. 10;  
FIG. 15 is an enlarged right side elevational view of the second embodiment of the probe shown in FIG. 10;  
FIG. 16 is an enlarged, broken away top plan view taken along line B-B on FIG. 10;  
FIG. 17 is an enlarged, broken away bottom plan view taken along line B-B on FIG. 10; and,  
FIG. 18 is another enlarged, broken away perspective view taken along line B-B on FIG. 10.  
The broken lines depict portions of the probe and form no part of the claimed design. The dash-dot-dash lines depict boundaries between claimed portion and unclaimed portion of the probe and form no part of the claimed design.

**1 Claim, 12 Drawing Sheets**



(58) **Field of Classification Search**

CPC ..... G01R 1/0675

See application file for complete search history.

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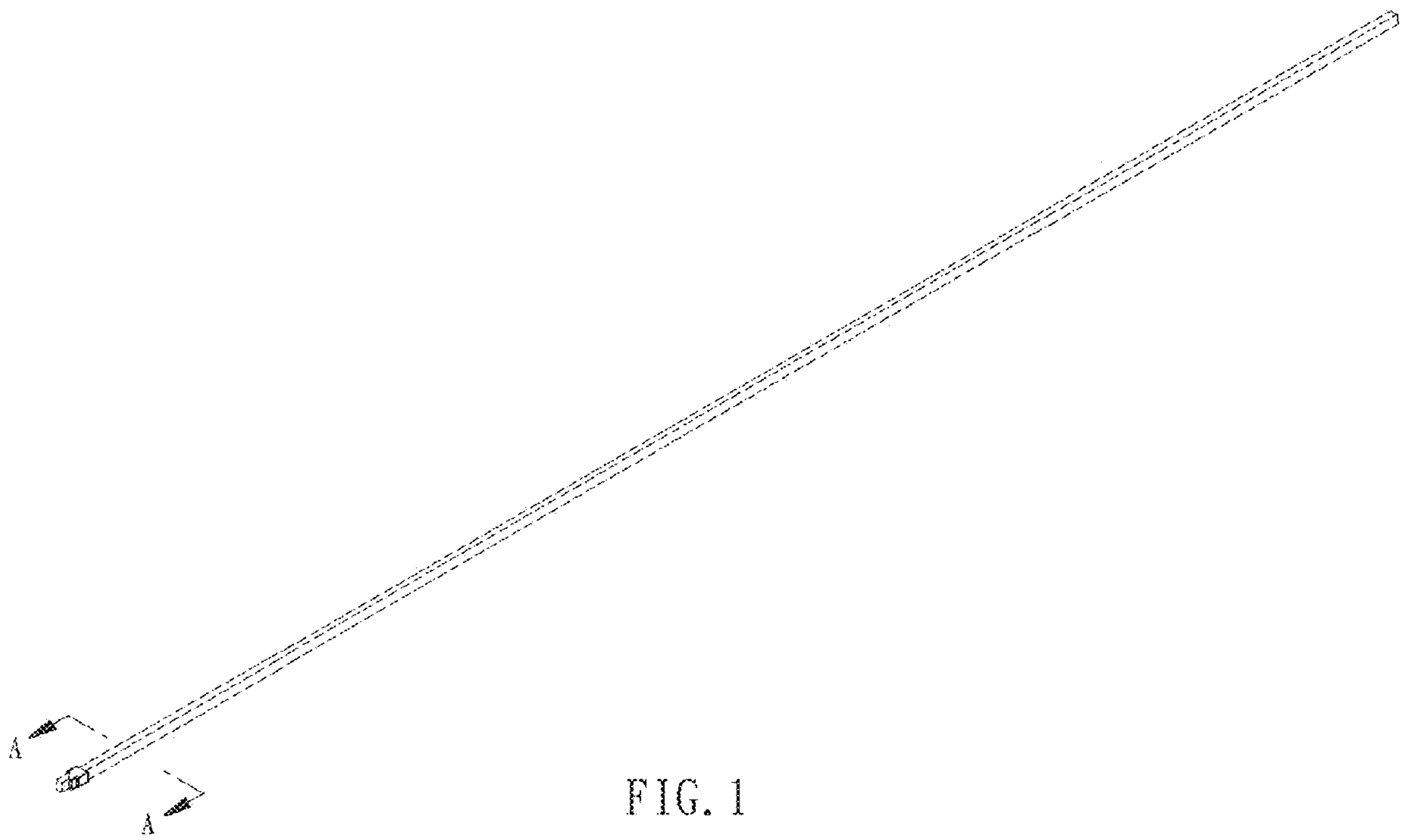


FIG. 1

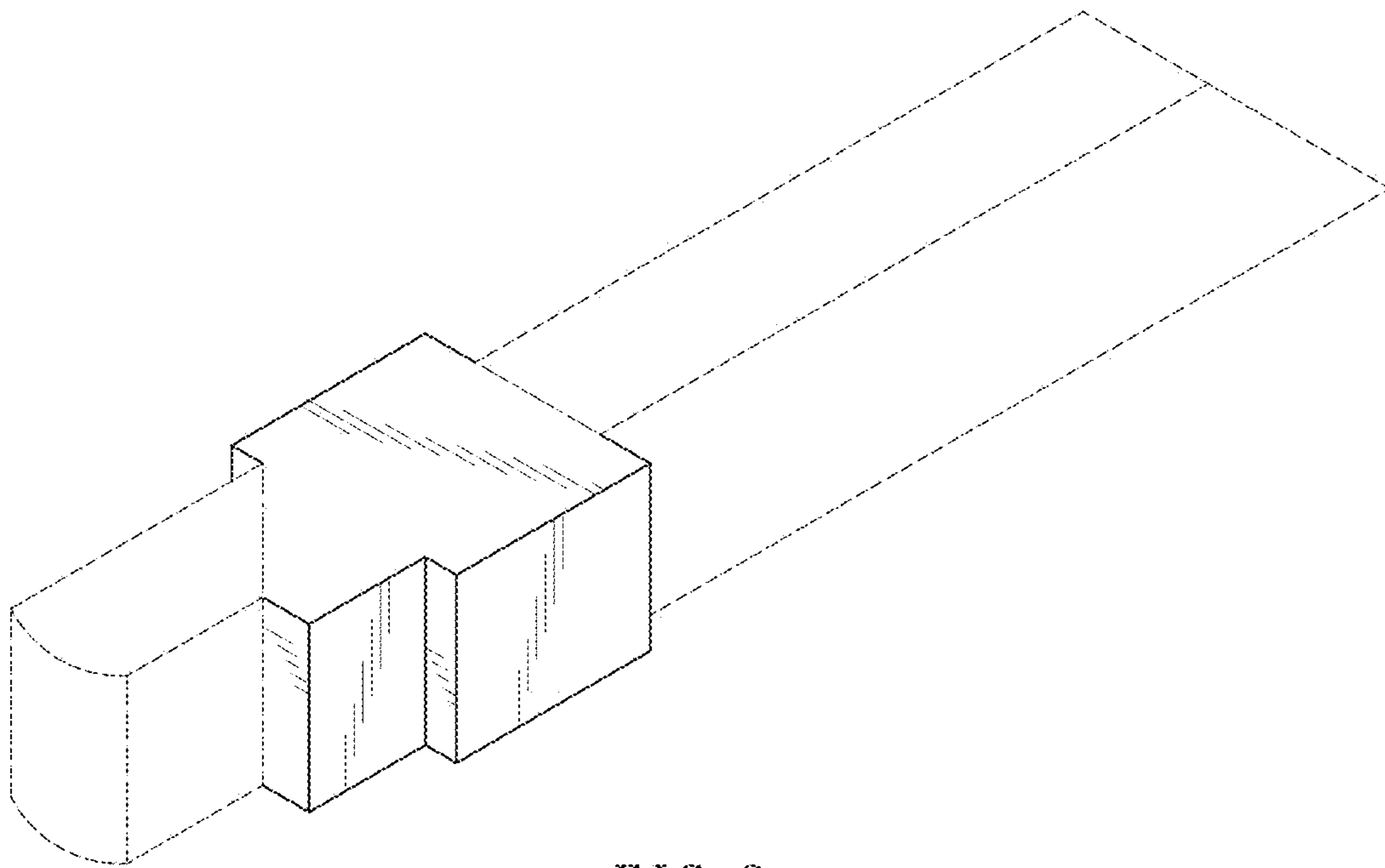


FIG. 2

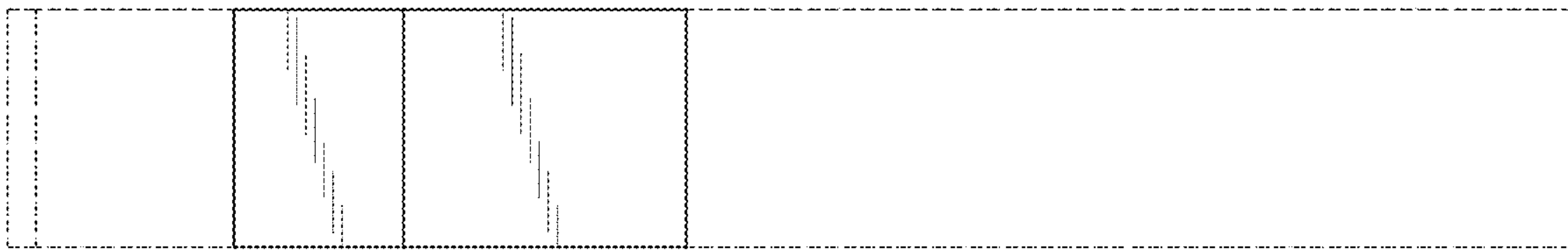


FIG. 3

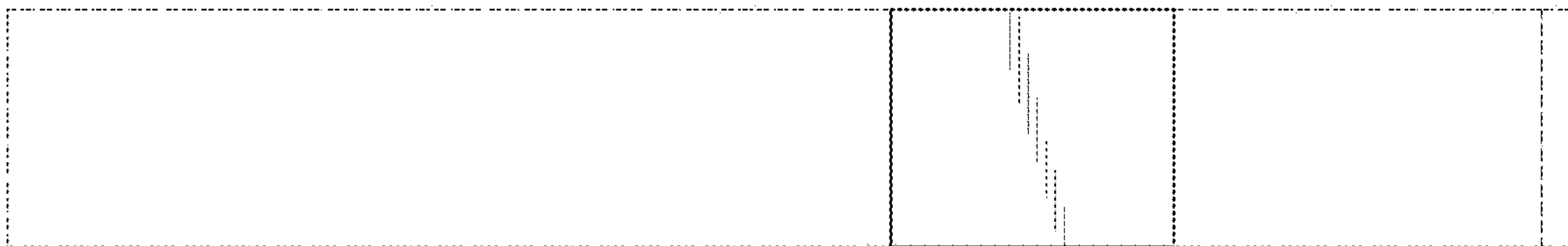


FIG. 4

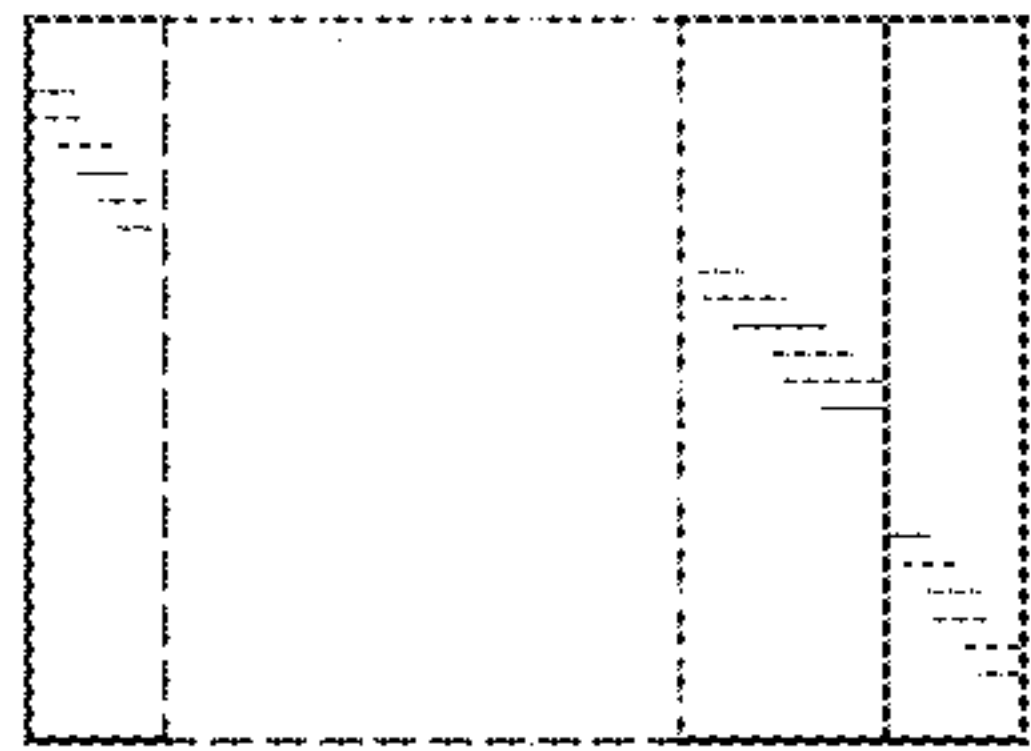


FIG. 5

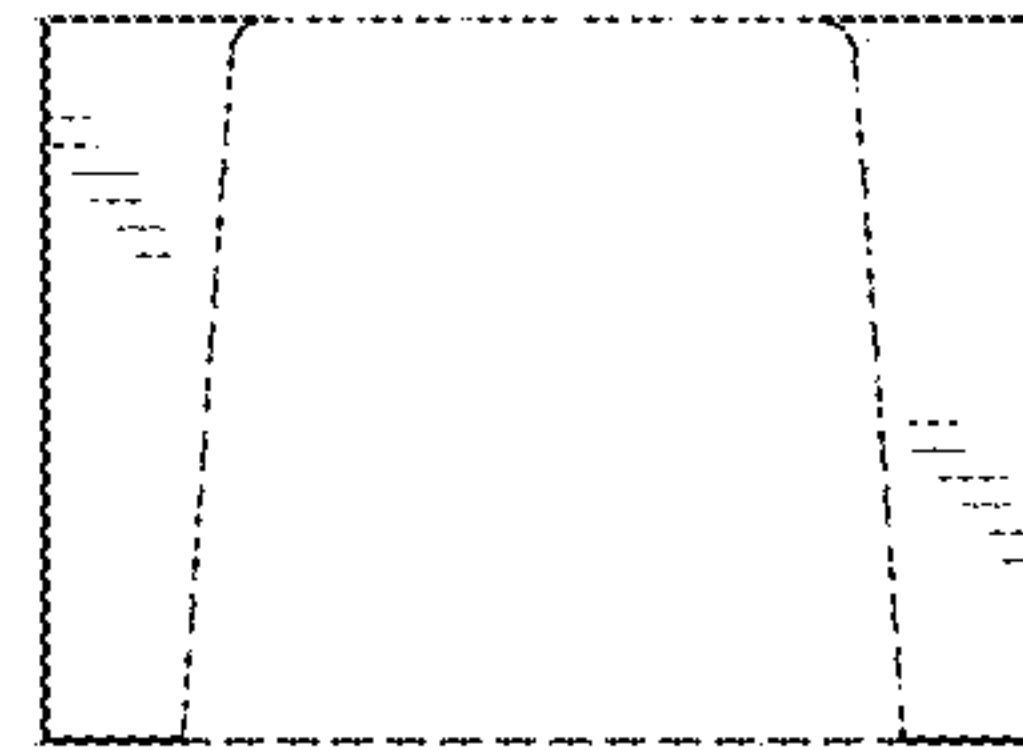


FIG. 6

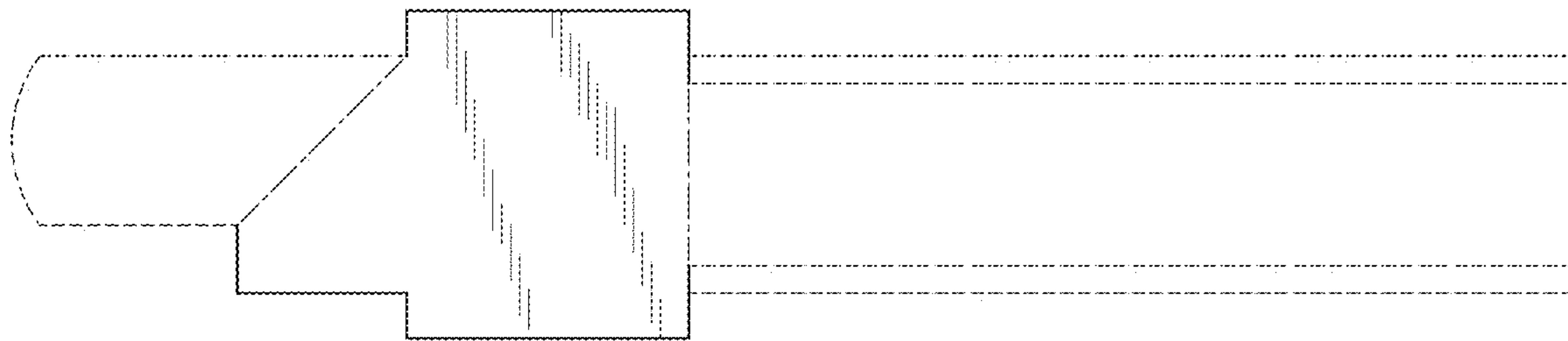


FIG. 7

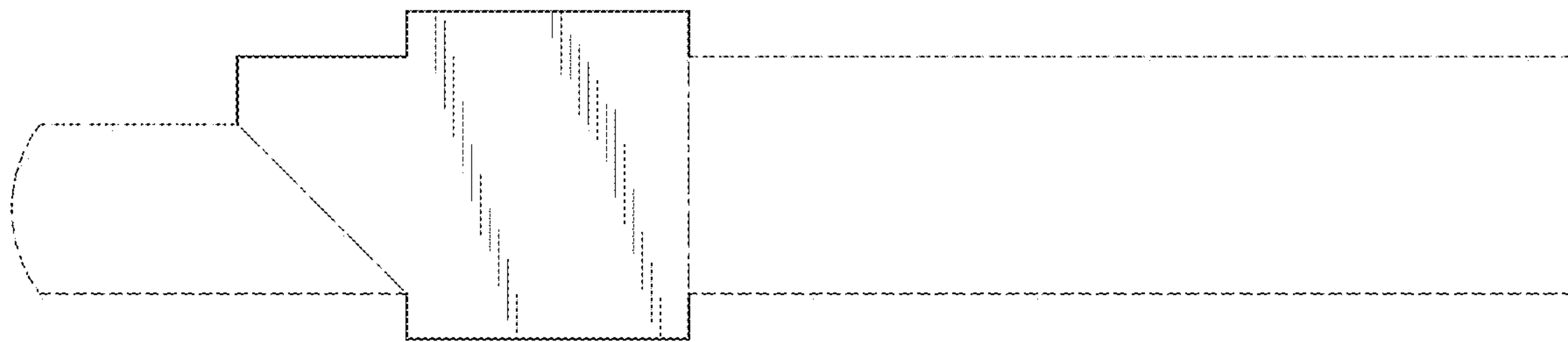


FIG. 8

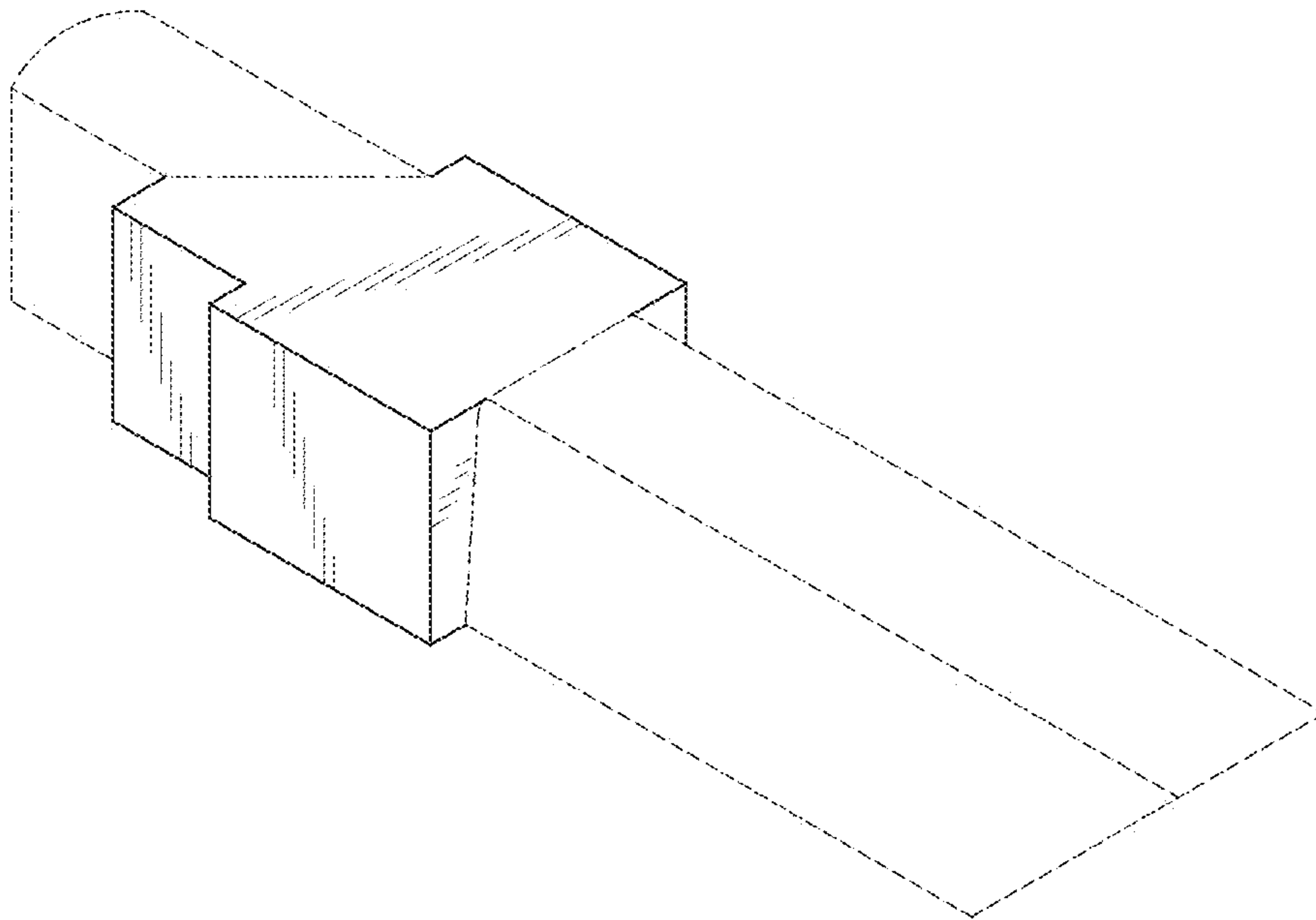


FIG. 9



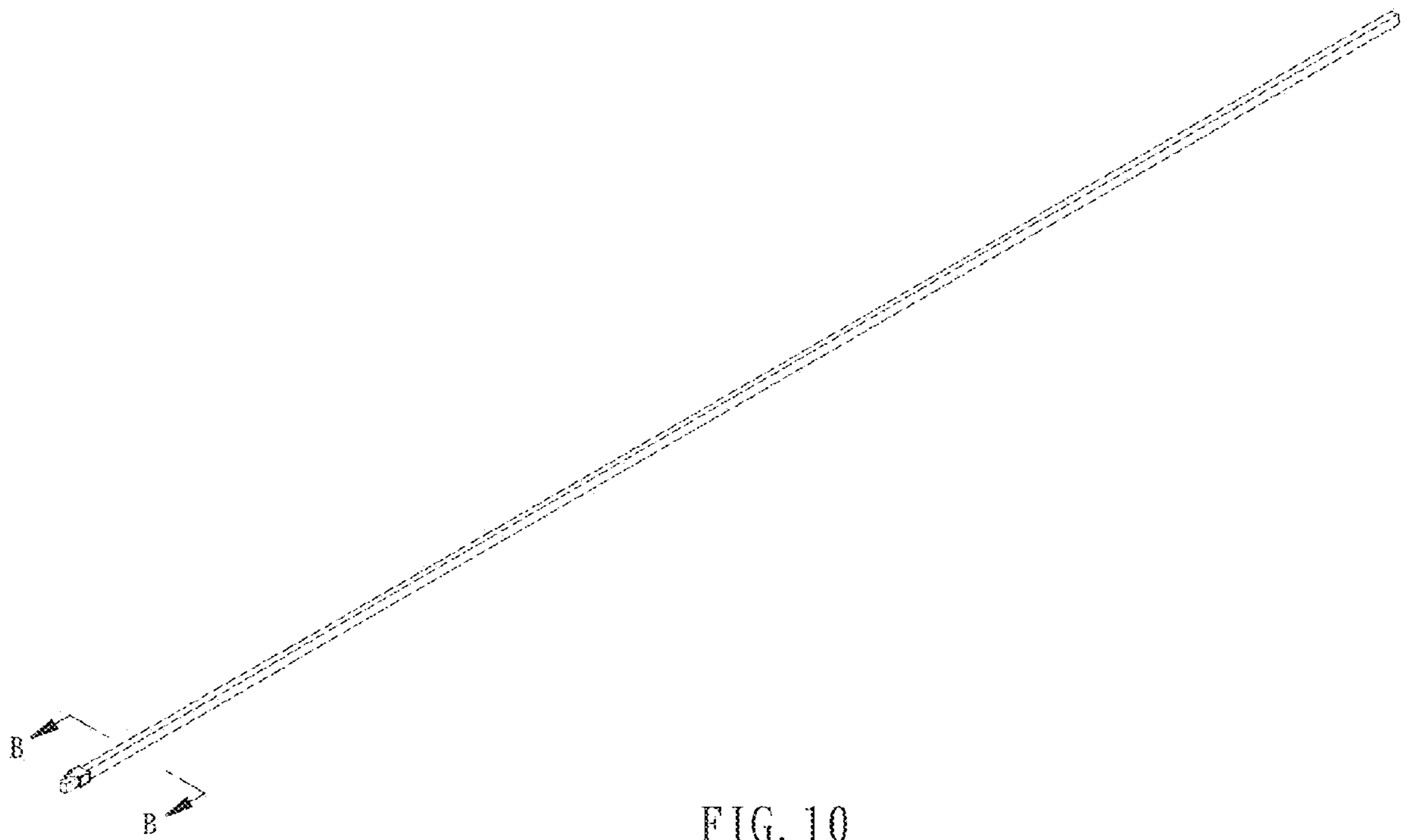


FIG. 10

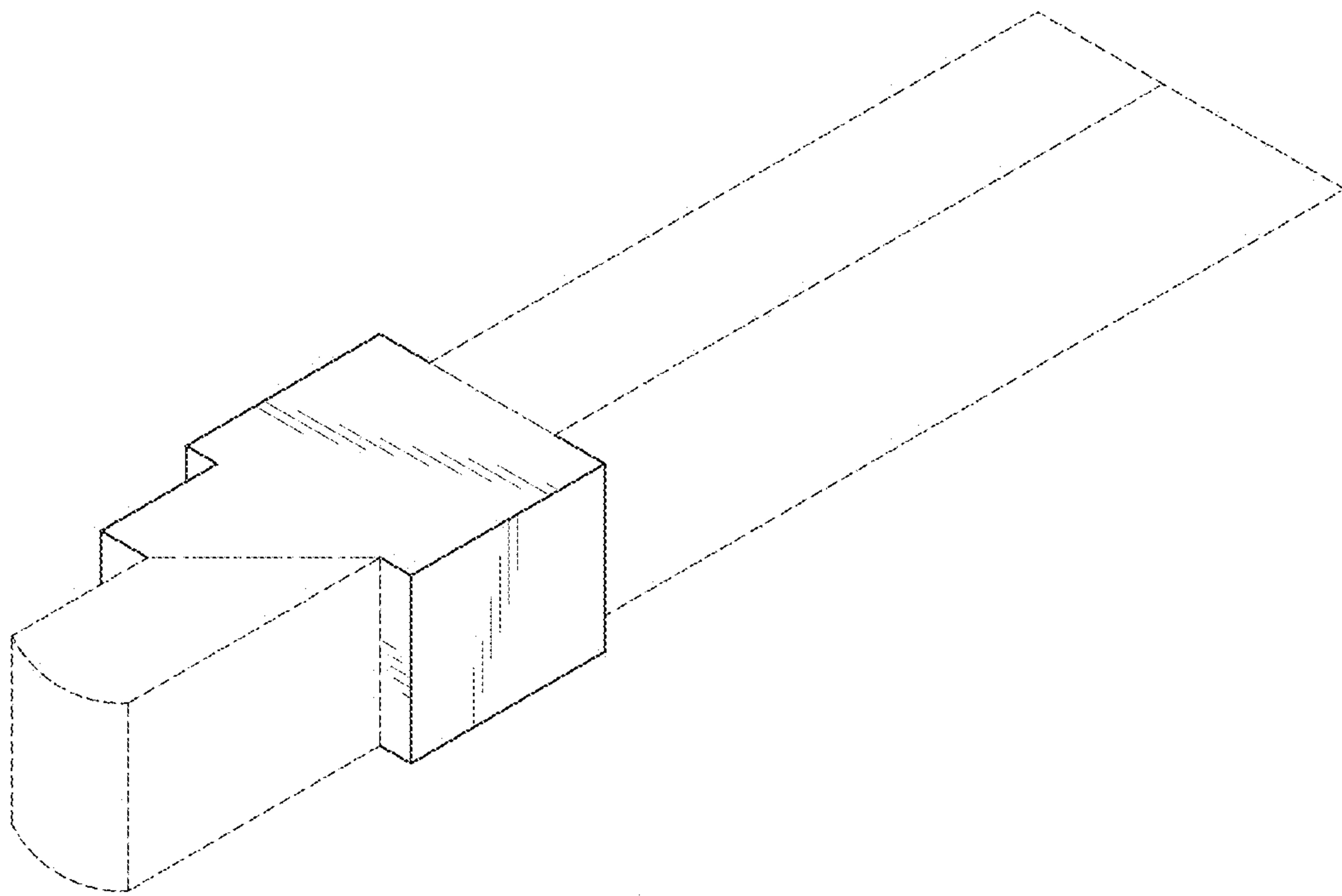


FIG. 11

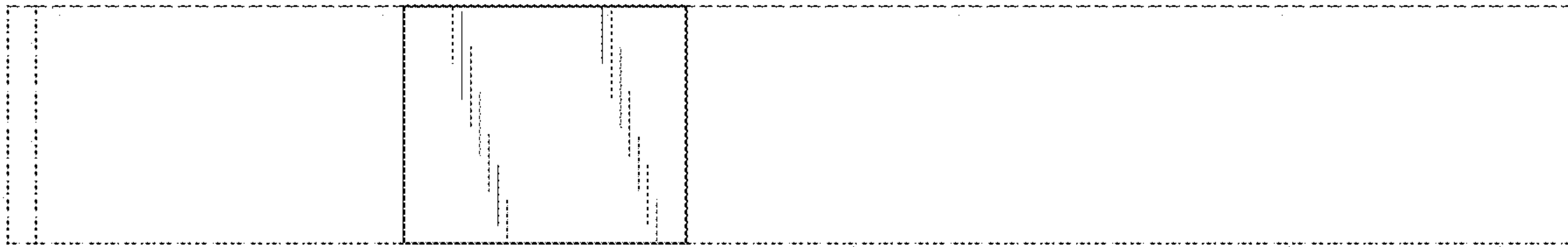


FIG. 12

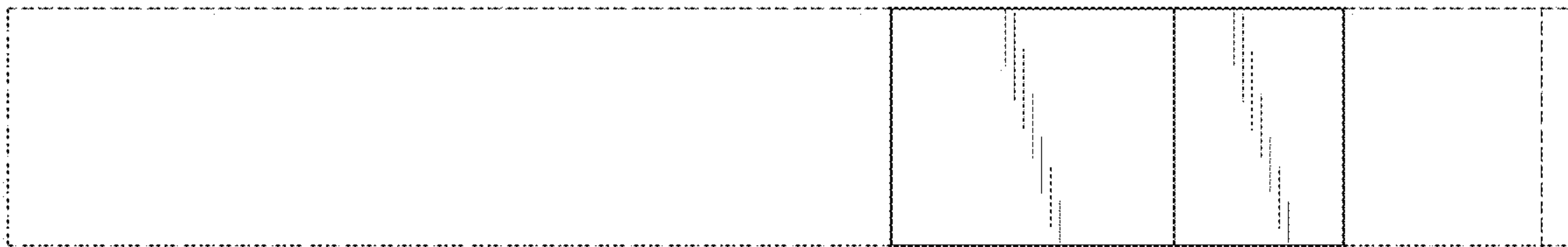


FIG. 13

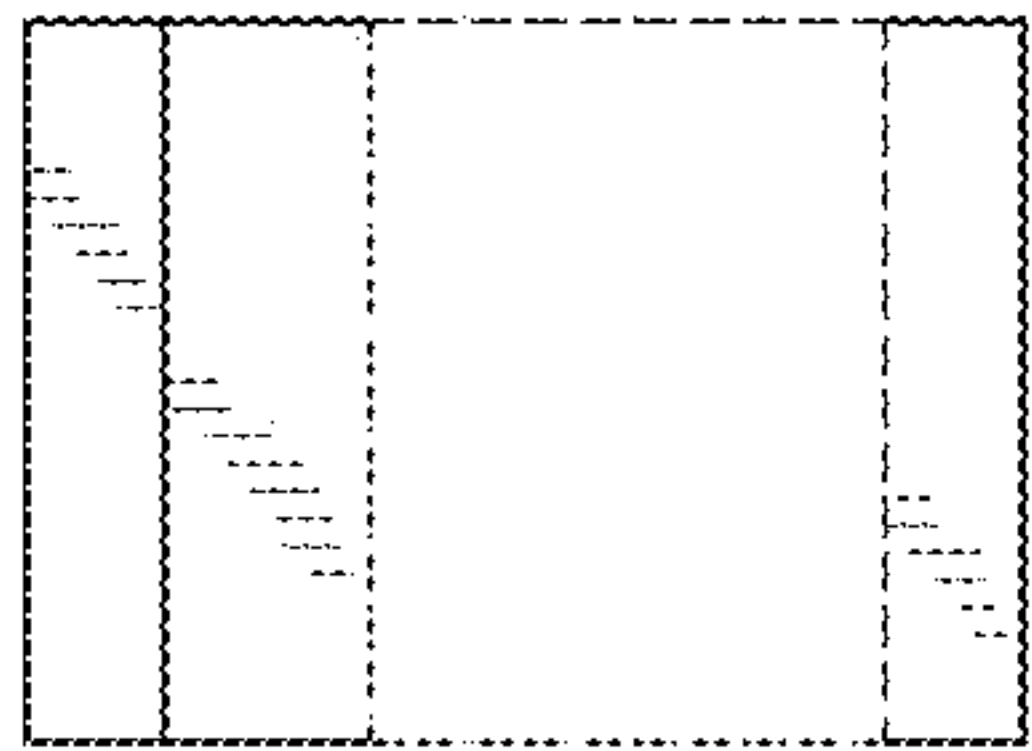


FIG. 14

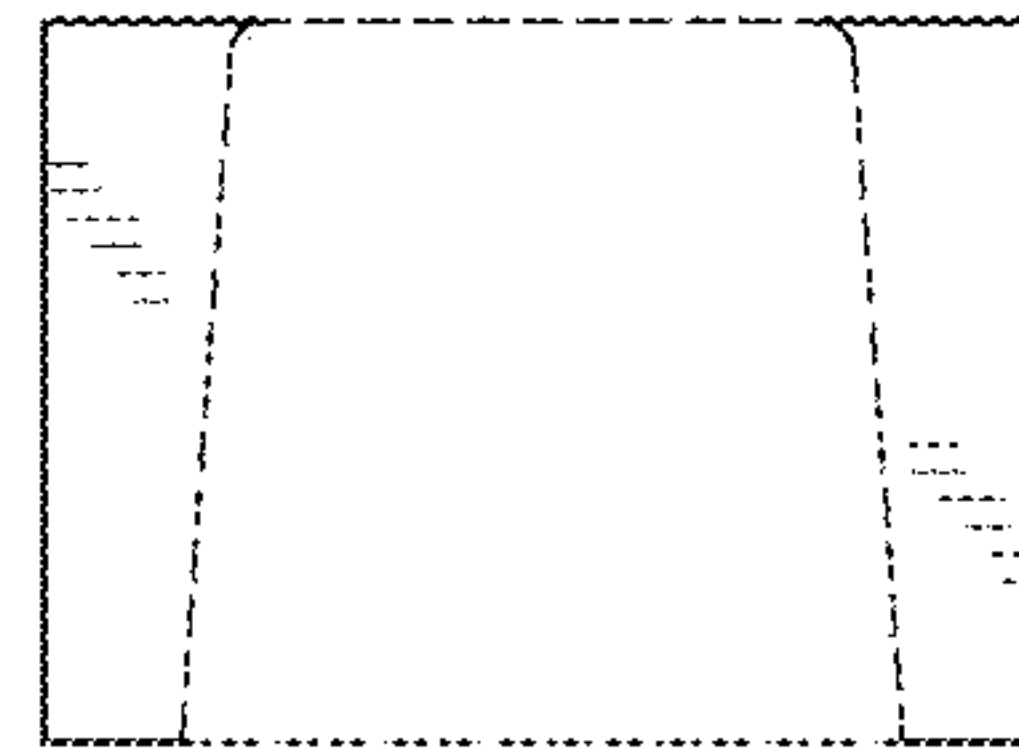


FIG. 15

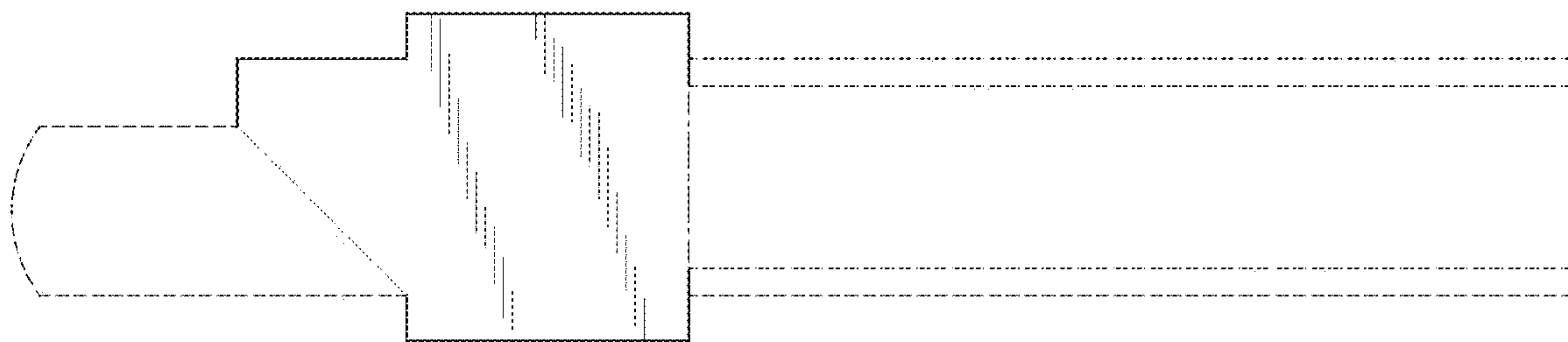


FIG. 16

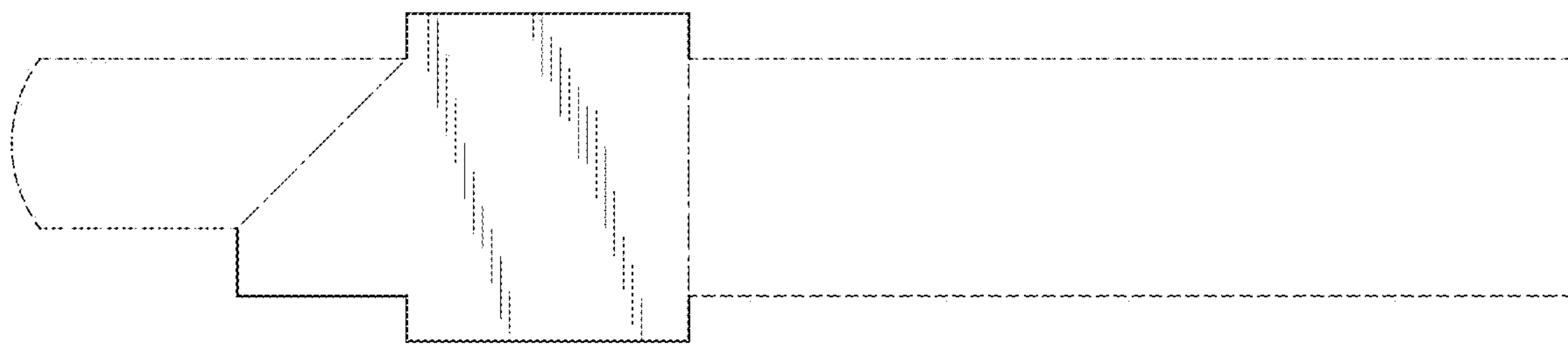


FIG. 17

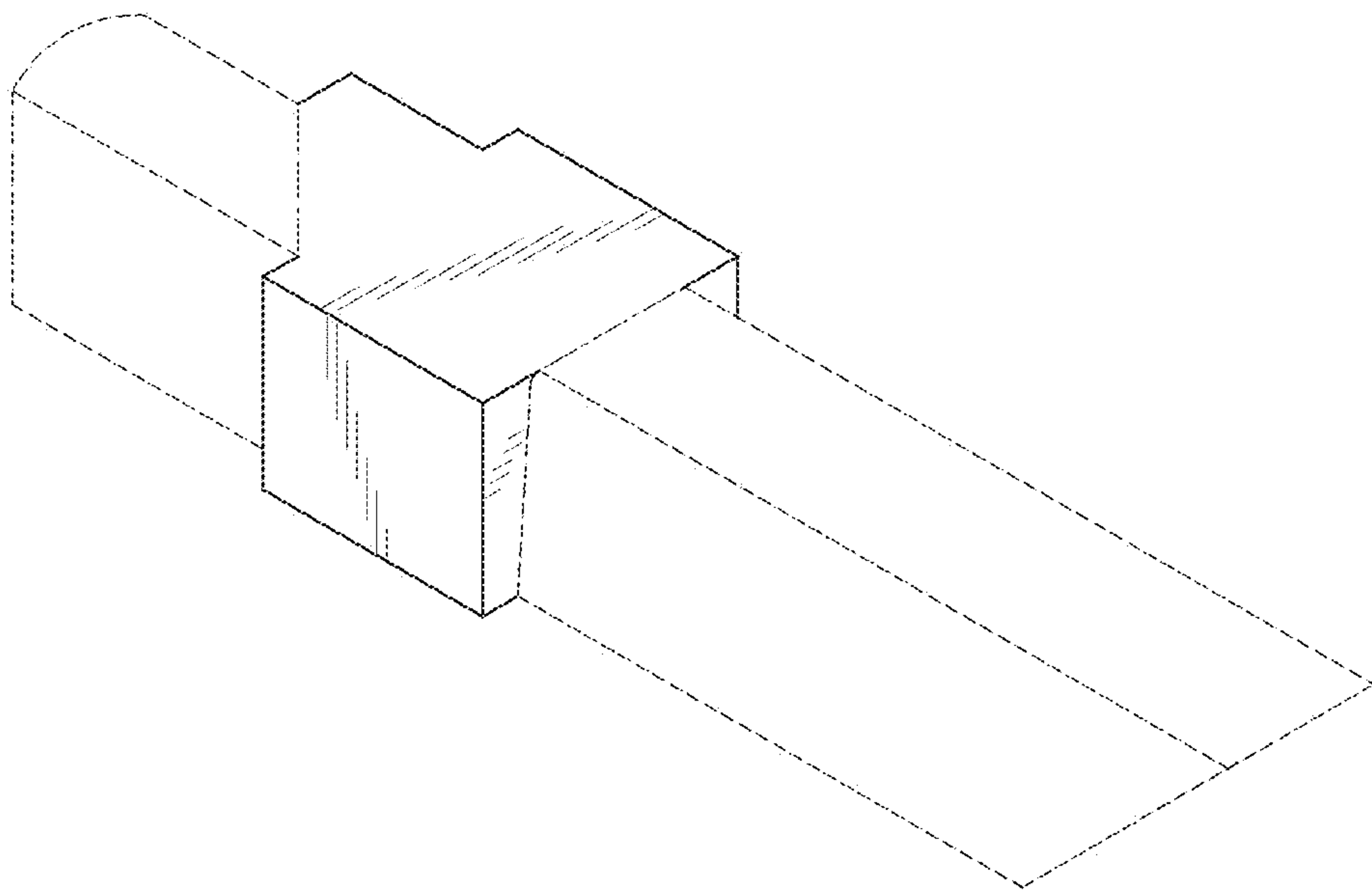


FIG. 18